

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/733,033	NISHINO ET AL.	
Examiner	Art Unit	
Tuan V. Ho	2615	

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Class	Subclass	Date	Examiner	
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	333.08 333.09	,	gar	

INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				
Ser	kanle	Vista	Ales				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Spark Unitory	4170s	2		
Inventor Kip Jeanh	2/12/00	æ		
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